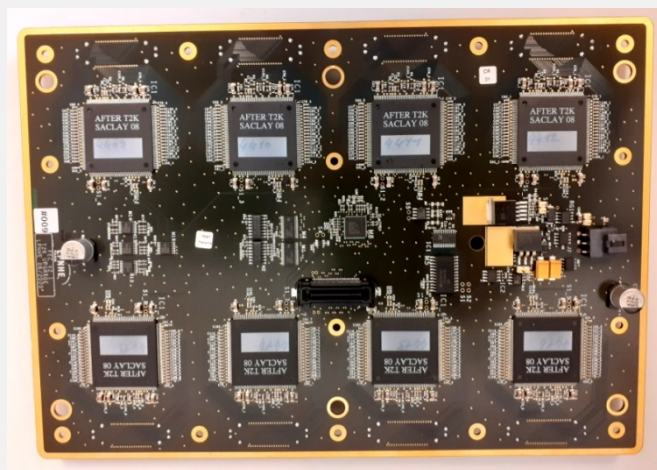


Front End Card - **FEC** / T2K Phase2



LPNHE electronics staff : *Eric Pierre*
 François Toussenet
 Jean-Marc Parraud

LPNHE scientist Manager : *Boris Popov*

Acknowledgements to *Denis Calvet* and all the *IRFU T2K team members* for their collaboration



HA-TPC front-end electronics PRR

⇒ FEC

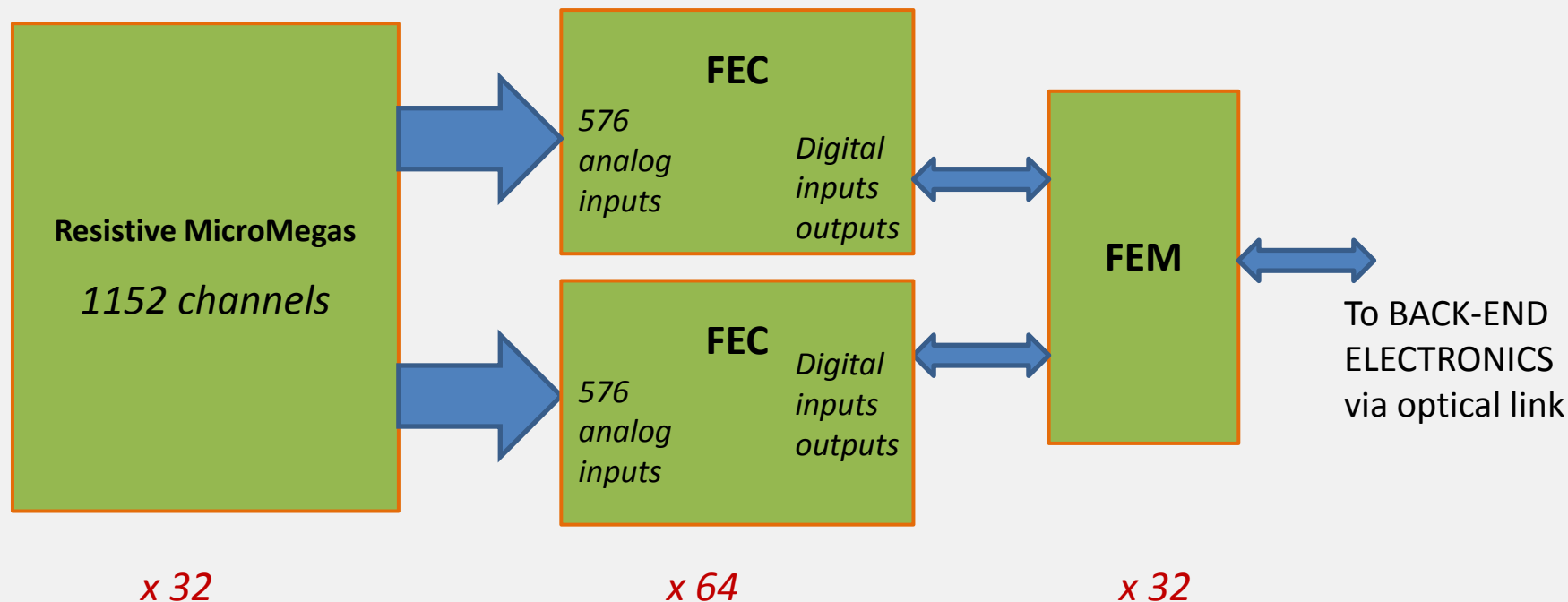
2020/10/29



Preliminary

DETECTOR

FRONT-END ELECTRONICS





HA-TPC front-end electronics PRR

⇒ FEC

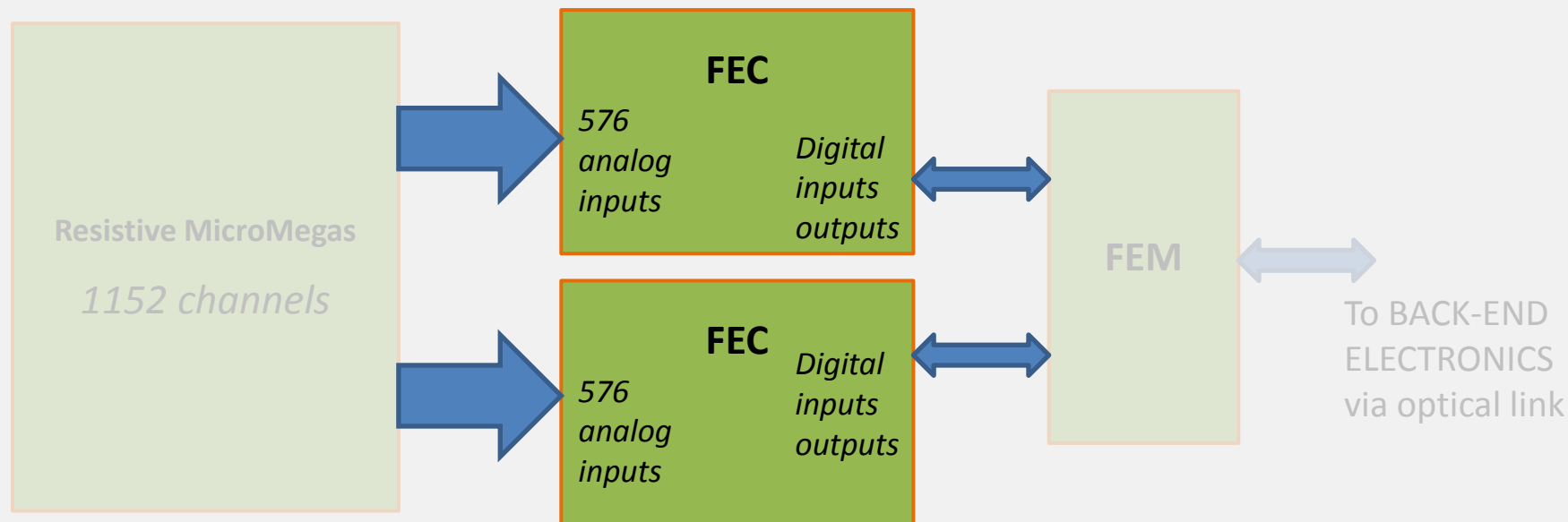
2020/10/29



Preliminary

DETECTOR

FRONT-END ELECTRONICS



64 x FEC needed for on-site integration + spares

LPNHE contribution

→ Production of **84 cards**: 12 x pre-prod cards
72 x prod cards

FEC / Phase2 :

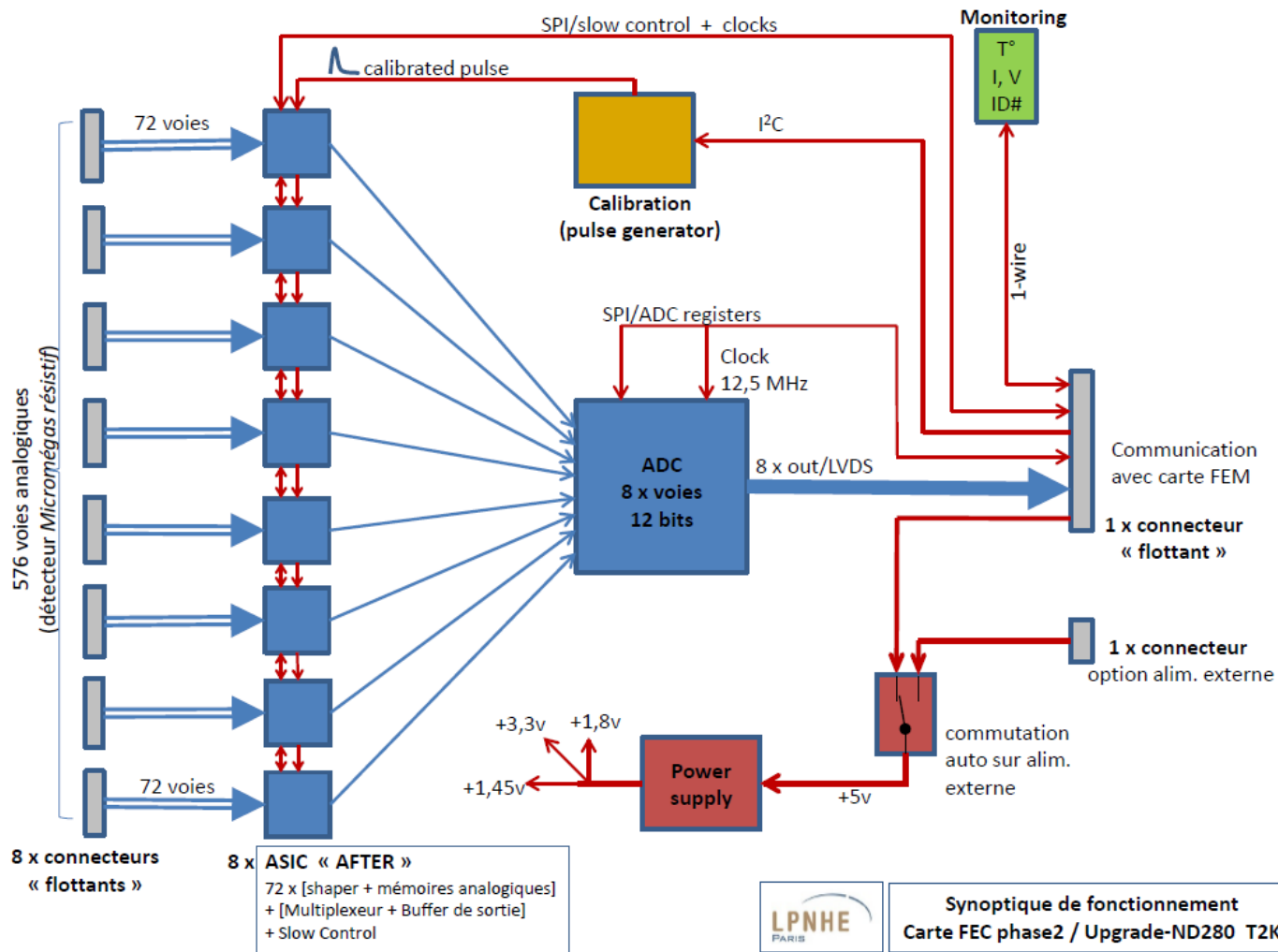
Based on FEC/Phase1 that works fine for more than 10 years at T2K-Tokai site.

Use of the **same ASIC** (→ « After » / IRFU) for the read out and processing of analog signals coming from the detector.

Qty=8 (qty=4 in Phase1)

Use of an **8 channel ADC** (AD9637-40), instead of a 4 channel ADC.

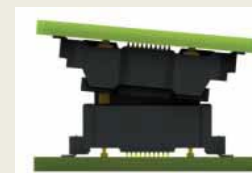
The **global architecture remains the same** as it was in Phase1.



How did it go till now :

- December 2018 : **1st FEC mock-up** *without active components*
- March 2019 : **2nd FEC mock-up** " " "
- ⇒ These mock-ups allowed the validation of **floating connectors**
intended for connecting signals : **MicroMegas detector** \longleftrightarrow **FEC** (8 connectors)
FEM \longleftrightarrow **FEC** (1 connector)

HIROSE FX23 series
80 contacts
+ 4 power contacts



- October 2019 : Design of the **FEC prototype schematics**, *including all final fonctionnalités*
- February 2020 : **FEC prototype manufacturing**
February to June 2020 : Tests at IRFU with FEM prototype and acquisition system
worked fine after few fixes (**2 wrong footprints**, **1 missing connection** on eFuse)
- August 2020 : **12 x pre-prod FEC manufacturing**, **few changes** versus **prototype** mentioned above
 - ⇒ September 2020 : 4 x tested at IRFU with pre-prod FEM and acquisition system
 - 2 x tested at Warsaw with their new testbench**work fine** / **now waiting for production, qty = 72**

Tests made on FEC
prototypes at IRFU

→ Thanks to Denis Calvet !

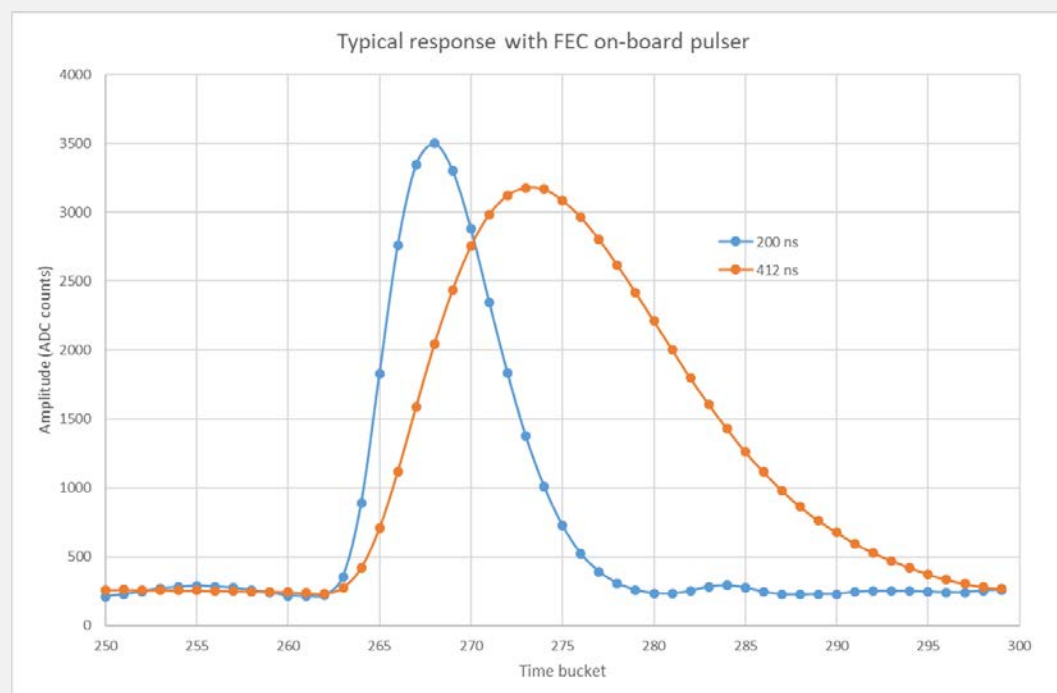
→ *Power consumption measurement : $\approx 1,5$ A / board*

→ *Calibration pulse
response
measurements*

2 pulse widths injected :

> 200 ns

> 412 ns



FEC-Proto-V1 n°05

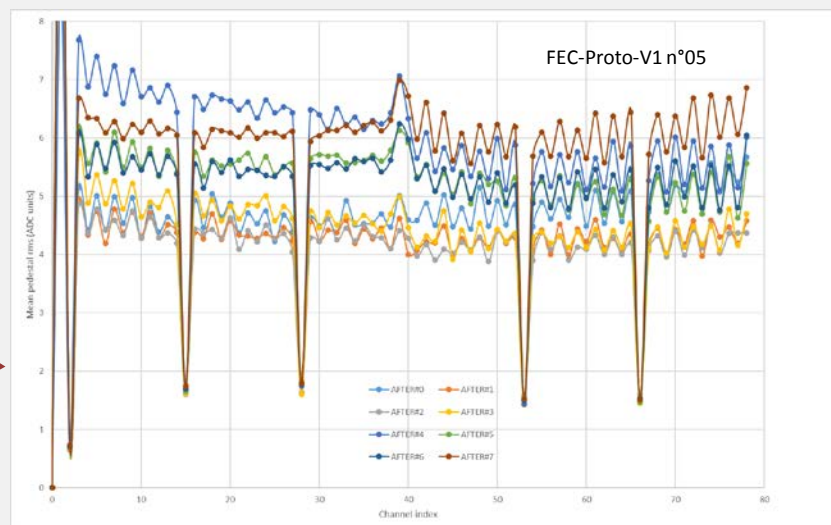
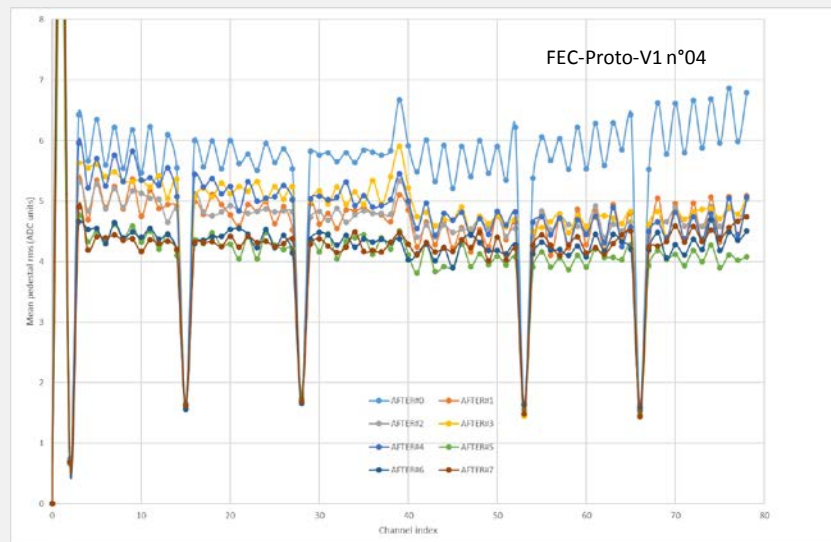
Tests made on FEC prototypes at IRFU

→ *Pedestals measurement*

- > *without shielding*
- > *inputs not connected*

! AFTER ASIC channels
0, 1, 2, 15, 28, 53, 66
are NOT data channels

(see document "ASIC After
datasheet", P. Baron and E.
Delagnes).



Test Bench intended for FEC production

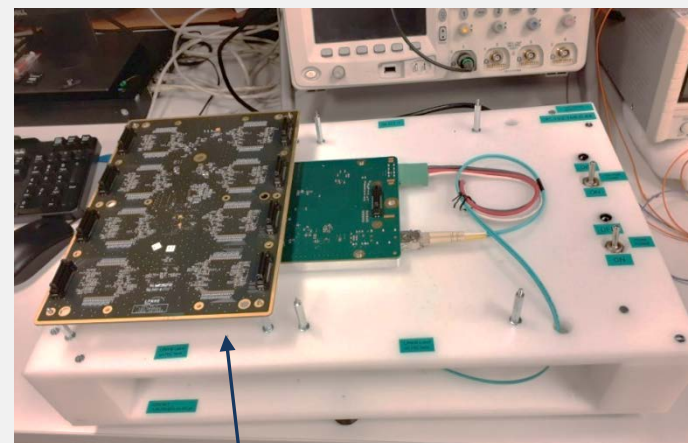
This testbench has been developed by our colleagues of Warsaw University of Technology, and *delivered to LPNHE one week ago.*

→ *Many thanks to our Warsaw colleagues for their good job.*

This testbench, including *hardware* and *software*, has been **successfully turned on at LPNHE.**

A few FEC tests have been performed.

>> In order to test the forthcoming FEC, this testbench *will be installed at the manufacturer site (Ouestronic-Rennes).*



FEC in test



HA-TPC front-end electronics PRR

⇒ FEC

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Test Bench intended for FEC production

« Passed » example
FEC 007 test report / page #1

Fec test report:			
Date: 2020-10-26 16:01:30			
Tester name: Diego			
Test#1 Monitoring values			
0	FEC label	007	Passed
1	FEC DC2438 ID	4300000244da9a26	OK
2	FEC_T (to 35°C)	26.495	OK
3	FEC_Vad (3.2V to 3.4V)	3.290	OK
4	FEC_I (1.1A to 1.5A)	1.366	OK
5	FEC_Vad (1.9V to 2.0V)	1.950	OK

Test#2 Slow control registers:			
Test#3 Pedestal run:			
8	After chip #8	Mean OK	STDEV OK
9	After chip #9	Mean OK	STDEV OK
10	After chip #10	Mean OK	STDEV OK
11	After chip #11	Mean OK	STDEV OK
12	After chip #12	Mean OK	STDEV OK
13	After chip #13	Mean OK	STDEV OK
14	After chip #14	Mean OK	STDEV OK
15	After chip #15	Mean OK	STDEV OK

Test#4 AD9637 test patterns			
0	ADC channel #0	P#1 (Midscale short 2048)	MAX 2048 MIN 2048
1	ADC channel #1	P#2 (+Full-scale short 4095)	MAX 4095 MIN 4095
2	ADC channel #2	P#4 (Checkerboard 1365 to 2730 toggle)	MAX 2730 MIN 1365
3	ADC channel #3	P#7 (One/zero-word toggle)	MAX 4095 MIN 0
4	ADC channel #4	P#1 (Midscale short 2048)	MAX 2048 MIN 2048
5	ADC channel #5	P#2 (+Full-scale short 4095)	MAX 4095 MIN 4095
6	ADC channel #6	P#4 (Checkerboard 1365 to 2730 toggle)	MAX 2730 MIN 1365
7	ADC channel #7	P#7 (One/zero-word toggle)	MAX 4095 MIN 0

Test#5 Pulser run			
8	After chip #8	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 3044
9	After chip #9	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 2974
10	After chip #10	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 3059
11	After chip #11	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 2966
12	After chip #12	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 3078
13	After chip #13	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 3029
14	After chip #14	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 3045
15	After chip #15	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 3025

FEC test final result: **Passed**

« Failed » example
FEC 009 test report / page #1

Fec test report:			
Date: 2020-10-26 16:13:43			
Tester name: Diego			
Test#1 Monitoring values			
0	FEC label	009	Failed
1	FEC DC2438 ID	6c00000244dc35c26	OK
2	FEC_T (to 35°C)	26.156	OK
3	FEC_Vad (3.2V to 3.4V)	3.270	OK
4	FEC_I (1.1A to 1.5A)	1.401	OK
5	FEC_Vad (1.9V to 2.0V)	1.330	FAIL

Test#2 Slow control registers:			
Test#3 Pedestal run:			
0	After chip #0	Mean OK	STDEV OK
1	After chip #1	Mean OK	STDEV OK
2	After chip #2	Mean OK	STDEV OK
3	After chip #3	Mean OK	STDEV OK
4	After chip #4	Mean OK	STDEV OK
5	After chip #5	Mean OK	STDEV OK
6	After chip #6	Mean OK	STDEV OK
7	After chip #7	Mean OK	STDEV OK

Test#4 AD9637 test patterns			
0	ADC channel #0	P#1 (Midscale short 2048)	MAX 2048 MIN 2048
1	ADC channel #1	P#2 (+Full-scale short 4095)	MAX 4095 MIN 4095
2	ADC channel #2	P#4 (Checkerboard 1365 to 2730 toggle)	MAX 2730 MIN 1365
3	ADC channel #3	P#7 (One/zero-word toggle)	MAX 4095 MIN 0
4	ADC channel #4	P#1 (Midscale short 2048)	MAX 2048 MIN 2048
5	ADC channel #5	P#2 (+Full-scale short 4095)	MAX 4095 MIN 4095
6	ADC channel #6	P#4 (Checkerboard 1365 to 2730 toggle)	MAX 2730 MIN 1365
7	ADC channel #7	P#7 (One/zero-word toggle)	MAX 4095 MIN 0

Test#5 Pulser run			
0	After chip #0	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 69
1	After chip #1	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 64
2	After chip #2	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 72
3	After chip #3	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 83
4	After chip #4	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 74
5	After chip #5	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 66
6	After chip #6	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 71
7	After chip #7	DAC: 483 Q(120) ADC(2850 to 3200)	ADC AMPL: 70

FEC test final result: **Failed**

SUMMARY of the first tests already done (qty : 8)

FEC #	Result	Comments
002	Passed	Tests made by Andrzej at Warsaw
003	Passed	
007	Passed	
008	Passed	
009	Failed	Faulty calibration pulse → To be solved
010	Passed	
011	Failed	I monitoring=1,501A NOT a failure (max = 1,5A)
012	Failed	too high pedestals on 5 channels / same Asic → needs more investigations

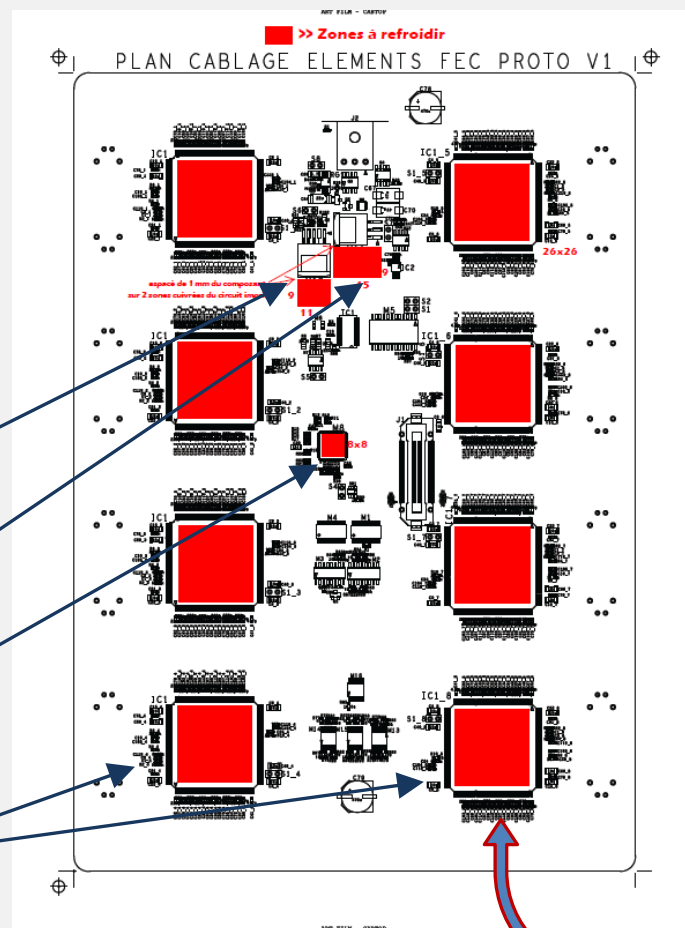
Range of acceptance may need to be revised

FEC cooling :

In order to keep a temperature of 25~30°C , cooling is required.

Components requiring cooling are :

- Regulator MIC29502
 $P \approx 2,5W$
- Regulator LM1086
 $P \approx 0,7W$
- ADC AD9637
 $P \approx 0,5W$
- Asic AFTER (x8)
 $P \approx 0,5W$ each



Shielding/cooling plate

Thanks to the IRFU mechanical team !

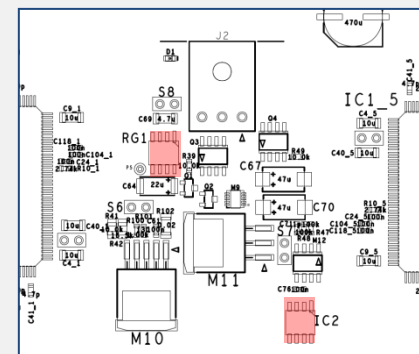


Silicone pads

Improvements made on FEC

Following the prototype tests :

- > Change of improper **footprints** → **IC2 / DS2438** (1-wire monitoring device)
RG1 / LP2951 (linear regulator / +1,45v)
- > Connection **GND** ↔ **Pad M9 / STEF05** (eFuse) that was missing !



Following the pre-prod FEC tests :

Current consumption

Monitoring :

Value adjustment of :

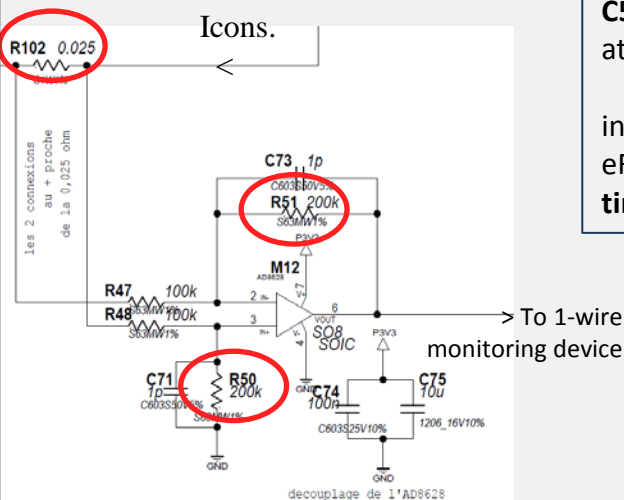
R50/R51 : 499 KΩ → 200 KΩ

R102 : 0,02 Ω → 0,025 Ω

in order to keep an ideal common mode voltage on M12 inputs

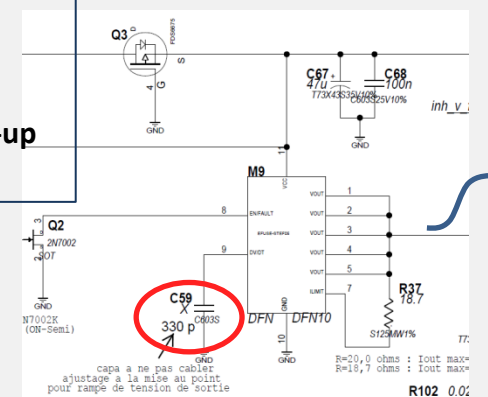
... But op-amp gain is divided per 2

→ *To be taken into account in the acquisition part*



C59 : value adjustment at 330 pF

in order to set the eFuse **output ramp-up time** at ~10 ms



Topics to keep an eye on

Tests in magnetic field :

Because of *Covid-19 pandemic*, beam tests could not take place in October 2020 (DESY) as planned. Thus, pre-prod FEC could not have been tested in a 0,2 T magnetic field.

→ There is an alternative to do this magnetic test at *IJCLab-Orsay*. Date to be determined. (? Covid ?)

→ We are rather confident to the issue : *FEC/Phase1* was insensitive to this environment.

FEC/Phase2 : no magnetic component, only 1 inductor-22 nH for the ADC/1,8v filtering.

This inductor is not mandatory and has been placed *as a precaution*.

>> It can safely be replaced by a 0 Ω resistor if necessary.

Analog inputs are not voltage-referenced :

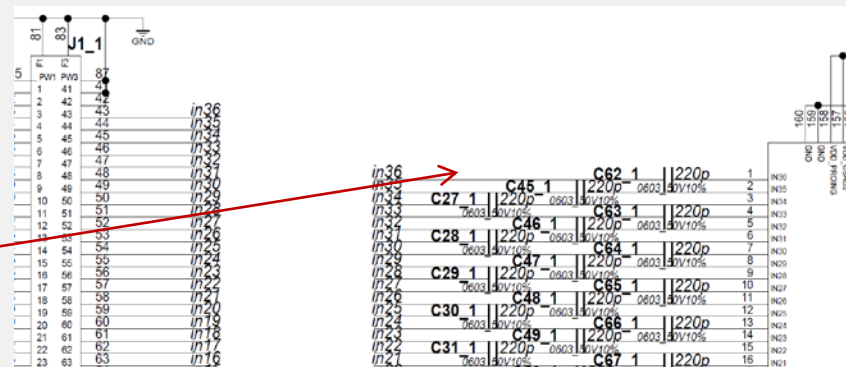
Input pads towards AFTER Asic are not referenced, and may eventually be charged at a potential greater than the one accepted by the Asic input.

→ Existing leakage currents on PCB must eliminate this possibility

→ No damage has never been observed till now

>> In series capacitors may be replaced by 1 kv ones

>> As a last resort, a 100 M Ω to GND can be added at each input pad (qty=576 !)





HA-TPC front-end electronics PRR

⇒ FEC

2020/10/29



Planned schedule : (before Covid-19 containment announcement)

FEC Boards

- November 2020 : **Launch of FEC prod** (qty=72) to external company (Ouestronic)
- End of February 2021 : 1st batch of **16 FEC** tested and delivered
⇒ These 16 boards are intended to equip the first ½ HA-TPC planned for March 2021
- April 2021 : Last batch of **56 FEC** tested and delivered

FEC Cooling plates

- November 2020 : **8 plates** manufactured at LPNHE workshop
- December 2020 : **8 plates** manufactured by external company (Chanteloup Associés)
⇒ These 16 cooling plates are intended to equip the first ½ HA-TPC planned for March 2021
- April 2021 : **64 plates** manufactured by external company (Chanteloup Associés)



HA-TPC front-end electronics PRR

⇒ FEC

2020/10/29



Risks of delay on the schedule :

- **COVID-19 !** Delay on our work at LPNHE in case of sanitary containment

Delay on **FEC production** → 😊 **Ouestronic** was open during previous containment, ... maybe the same for next one

Delay on **cooling plates production**. No information about **Chanteloup Associés** in that case